PHU101NQ03LT

N-channel TrenchMOS logic level FET

Rev. 04 — 30 June 2009

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Simple gate drive required due to low gate charge
- Suitable for logic level gate drive sources

1.3 Applications

■ DC-to-DC convertors

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	30	V
I _D	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V};$ see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	75	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	166	W
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 5 \text{ V}; I_D = 50 \text{ A};$ $V_{DS} = 15 \text{ V}; T_j = 25 \text{ °C};$ see Figure 11	-	8	-	nC
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 9}}{\text{10}};$ $S_j = \frac{\text{Figure 10}}{\text{10}}$	-	4.5	5.5	mΩ



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol	
1	G	gate		_	
2	D	drain	mb	D	
3	S	source		$G \longrightarrow \overline{A}$	
mb	D	mounting base; connected to drain	1 2 3	mbb076 S	
			SOT533 (IPAK)		

3. Ordering information

Table 3. Ordering information

Type number	Package				
	Name	Description	Version		
PHU101NQ03LT	IPAK	plastic single-ended package (IPAK); 3 leads (in-line)	SOT533		

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	30	V
V_{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	30	V
V_{GS}	gate-source voltage		-20	20	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure 1</u>	-	75	Α
		V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	75	Α
I _{DM}	peak drain current	$t_p \le 10 \mu\text{s}; \text{ pulsed}; T_{mb} = 25 ^{\circ}\text{C}; \text{ see } \underline{\text{Figure 3}}$	-	240	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	166	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
V_{GSM}	peak gate-source voltage	pulsed; $δ = 25$ %; $T_j ≤ 150$ °C; $t_p ≤ 50$ μs	-25	25	V
Source-dra	ain diode				
Is	source current	$T_{mb} = 25 ^{\circ}C$	-	75	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	240	Α
Avalanche	ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 43 A; V_{sup} ≤ 15 V; unclamped; t_p = 0.19 ms; R_{GS} = 50 Ω	-	185	mJ

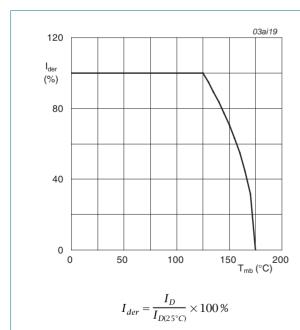
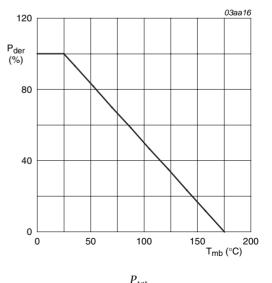
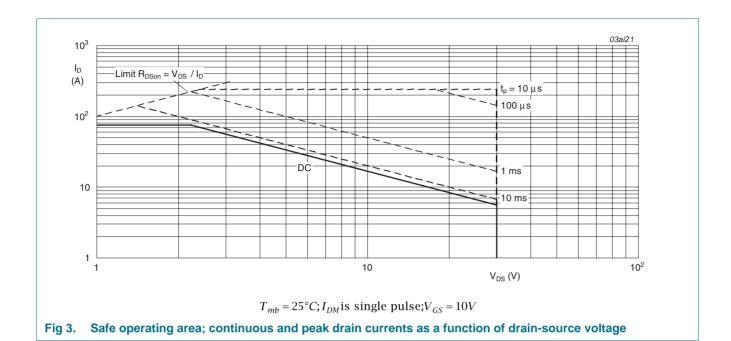


Fig 1. Normalized continuous drain current as a function of mounting base temperature



 $P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$

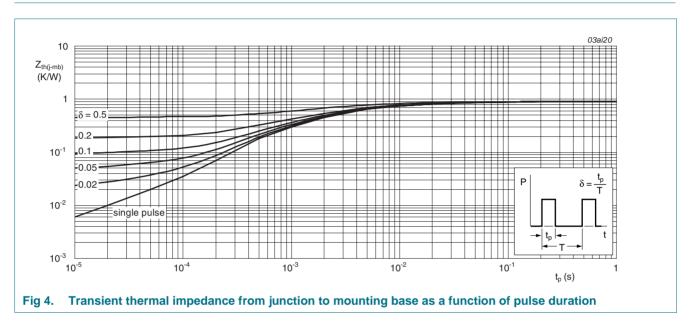
Fig 2. Normalized total power dissipation as a function of mounting base temperature



5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see <u>Figure 4</u>	-	-	0.19	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	vertical in free air	-	70	-	K/W



6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
$V_{(BR)DSS}$	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	27	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ °C}$; see <u>Figure 7</u> ; see <u>Figure 8</u>	-	-	2.9	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 175 °C; see <u>Figure 7</u> ; see <u>Figure 8</u>	0.6	-	-	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C; see <u>Figure 7</u> ; see <u>Figure 8</u>	1	1.9	2.5	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.05	1	μA
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nA
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nA
R _{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 25 A; T_j = 25 °C; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	4.5	5.5	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 175 °C;$ see <u>Figure 9</u> ; see <u>Figure 10</u>	-	10.5	13.5	mΩ
		$V_{GS} = 5 \text{ V}$; $I_D = 25 \text{ A}$; $T_j = 25 \text{ °C}$; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	5.8	7.5	mΩ
Dynamic (characteristics					
Q _{G(tot)}	total gate charge	$I_D = 50 \text{ A}$; $V_{DS} = 15 \text{ V}$; $V_{GS} = 5 \text{ V}$;	-	23	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 11</u>	-	10.5	-	nC
Q_{GD}	gate-drain charge		-	8	-	nC
C _{iss}	input capacitance	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	2180	-	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 12</u>	-	600	-	pF
C _{rss}	reverse transfer capacitance		-	225	-	pF
t _{d(on)}	turn-on delay time	V_{DS} = 15 V; R_L = 0.6 Ω ; V_{GS} = 4.5 V;	-	23	-	ns
t _r	rise time	$R_{G(ext)} = 5.6 \Omega; T_j = 25 \text{ °C}; I_D = 25 \text{ A}$	-	90	-	ns
t _{d(off)}	turn-off delay time		-	37	-	ns
t _f	fall time		-	33	-	ns
Source-di	rain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see <u>Figure 13</u>	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 10 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$;	-	37	-	ns
Q _r	recovered charge	$V_{DS} = 25 \text{ V; } T_j = 25 \text{ °C}$	-	33	-	nC
	<u> </u>		-			

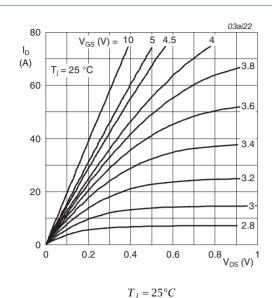
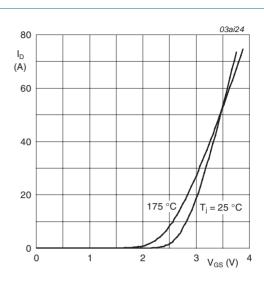
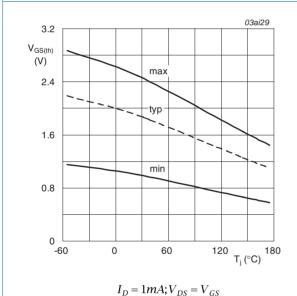


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



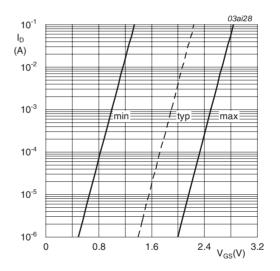
 $T_j = 25$ °C and 175°C; $V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values



ig 7. Gate-source threshold voltage as a function of

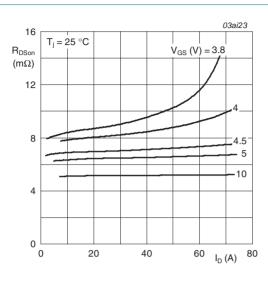
junction temperature



 $T_j=25$ °C; $V_{DS}=5V$

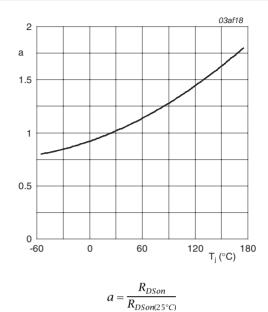
Fig 8. Sub-threshold drain current as a function of gate-source voltage

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 $T_i = 25^{\circ}C$

Drain-source on-state resistance as a function of drain current; typical values



 $R_{DSon(25^{\circ}C)}$ red drain-source on-state resis

Fig 10. Normalized drain-source on-state resistance factor as a function of junction temperature

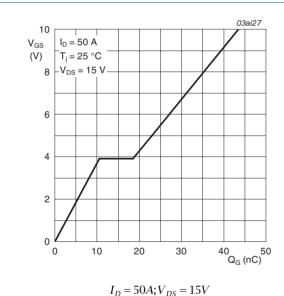
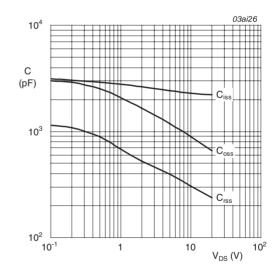


Fig 11. Gate-source voltage as a function of gate

charge; typical values



 $V_{GS} = 0V; f = 1MHz$

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

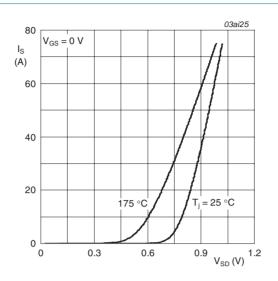
Fig 9.

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 $T_j = 25^{\circ} C \text{ and } 175^{\circ} C; V_{GS} = 0V$

Fig 13. Source current as a function of source-drain voltage; typical values

7. Package outline

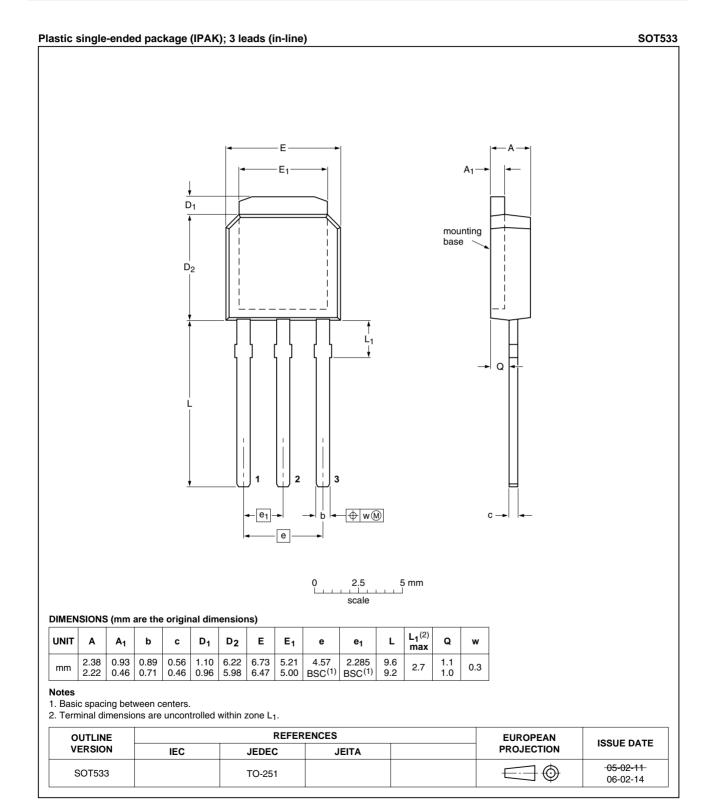


Fig 14. Package outline SOT533 (IPAK)

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Revision history

Table 7. **Revision history**

Product data sheet

Document ID	Release date	Data sheet status	Change notice	Supersedes
PHU101NQ03LT_4	20090630	Product data sheet	-	PHP_PHU101NQ03LT_3
Modifications:	 The format of this guidelines of NXP 	data sheet has been re Semiconductors.	edesigned to comply	with the new identity
	 Legal texts have b 	een adapted to the ne	w company name wh	nere appropriate.
	 Type number PHL 	J101NQ03LT separate	d from data sheet PH	HP_PHU101NQ03LT_3.
PHP_PHU101NQ03LT_3	20051117	Product data sheet	CPC # 200309016	PHP_PHU101NQ03LT-02
PHP_PHU101NQ03LT-02 (9397 750 10927)	20030225	Product data	-	PHP_PHD_PHB_PHU101 NQ03LT-01
PHP_PHD_PHB_PHU101 NQ03LT-01 (9397 750 09307)	20020220	Product data	-	-

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9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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